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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

-XF

Details	
Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	2560
Number of I/O	202
Number of Gates	54000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	272-BBGA
Supplier Device Package	272-PBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx36-bgg272m

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Power Matters."

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1 Revision History

The revision history describes the changes that were implemented in the document. The changes are listed by revision, starting with the most current publication.

1.1 Revision 15.0

The following is a summary of the changes in revision 15.0 of this document.

- Table 15, page 21 is edited to add the footnote, VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V
- Table 22, page 25 is edited to add the footnote, VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V
- Table 23, page 25 is edited to add the footnote, VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V

1.2 Revision 14.0

The following is a summary of the changes in revision 14.0 of this document.

- Added CQFP package information for A42MX16 device in Product Profile, page 1 and Ceramic Device Resources, page 4 (SAR 79522).
- Added Military (M) and MIL-STD-883 Class B (B) grades for CPGA 132 Package and added Commercial (C), Military (M), and MIL-STD-883 Class B (B) grades for CQFP 172 Package in Temperature Grade Offerings, page 5 (SAR 79519)
 - Changed Silicon Sculptor II to Silicon Sculptor in Programming, page 12 (SAR 38754)
- Added Figure 53, page 158 CQ172 package (SAR 79522).

1.3 **Revision 13.0**

The following is a summary of the changes in revision 13.0 of this document.

- Added Figure 42, page 97 PQ144 Package for A42MX09 device (SAR 69776)
- Added Figure 52, page 153 PQ132 Package for A42MX09 device (SAR 69776)

1.4 **Revision 12.0**

The following is a summary of the changes in revision 12.0 of this document.

- Added information on power-up behavior for A42MX24 and A42MX36 devices to the Power Supply, page 13 (SAR 42096
- Corrected the inadvertent mistake in the naming of the PL68 pin assignment table (SARs 48999, 49793)

1.5 **Revision 11.0**

The following is a summary of the changes in revision 11.0 of this document.

- The FuseLock logo and accompanying text was removed from the User Security, page 12. This marking is no longer used on Microsemi devices (PCN 0915)
- The Development Tool Support, page 19 was updated (SAR 38512)

1.6 Revision 10.0

The following is a summary of the changes in revision 10.0 of this document.

- Ordering Information, page 3 was updated to include lead-free package ordering codes (SAR 21968)
- The User Security, page 12 was revised to clarify that although no existing security measures can give an absolute guarantee, Microsemi FPGAs implement the best security available in the industry (SAR 34673)



Additionally, the back-annotation flow is compatible with all the major simulators and the simulation results can be cross-probed with Silicon Explorer II, Microsemi's integrated verification and logic analysis tool. Another tool included in the Libero software is the SmartGen macro builder, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design.

Microsemi's Libero software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synopsys, and Cadence design systems.

See the Libero IDE web content at www.microsemi.com/soc/products/software/libero/default.aspx for further information on licensing and current operating system support.

3.6 Related Documents

The following sections give the list of related documents which can be refered for this datasheet.

3.6.1 Application Notes

- AC278: BSDL Files Format Description
- AC225: Programming Antifuse Devices
- AC168: Implementation of Security in Microsemi Antifuse FPGAs

3.6.2 User Guides and Manuals

- Antifuse Macro Library Guide
- Silicon Sculptor Programmers User Guide

3.6.3 Miscellaneous

Libero IDE Flow Diagram

3.7 5.0 V Operating Conditions

The following tables show 5.0 V operating conditions.

Table 12 • Absolute Maximum Ratings for 40MX Devices*

Symbol	Parameter	Limits	Units
VCC	DC Supply Voltage	-0.5 to +7.0	V
VI	Input Voltage	-0.5 to VCC+0.5	V
VO	Output Voltage	-0.5 to VCC+0.5	V
t _{STG}	Storage Temperature	-65 to +150	°C

Note: *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the recommended operating conditions.

Table 13 • Absolute Maximum Ratings for 42MX Devices*

Symbol	Parameter	Limits	Units
VCCI	DC Supply Voltage for I/Os	-0.5 to +7.0	V
VCCA	DC Supply Voltage for Array	-0.5 to +7.0	V
VI	Input Voltage	-0.5 to VCCI+0.5	V
VO	Output Voltage	-0.5 to VCCI+0.5	V
t _{STG}	Storage Temperature	-65 to +150	°C



3.9.1 Mixed 5.0V/3.3V Electrical Specifications

		Com	mercial	Com	mercial –F	Indu	strial	Milit		
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
VOH ¹	IOH = -10 mA	2.4		2.4						V
	IOH = -4 mA					2.4		2.4		V
VOL ¹	IOL = 10 mA		0.5		0.5					V
	IOL = 6 mA						0.4		0.4	V
VIL		-0.3	0.8	-0.3	0.8	-0.3	0.8	-0.3	0.8	V
VIH ²		2.0	VCCA + 0.3	2.0	VCCA + 0.3	2.0	VCCA + 0.3	2.0	VCCA + 0.3	V
IL	VIN = 0.5 V		-10		-10		-10		-10	μA
IH	VIN = 2.7 V		-10		-10		-10		-10	μA
Input Transition Time, T_R and T_F			500		500		500		500	ns
CIO I/O Capacitance			10		10		10		10	pF
Standby Current,	A42MX09		5		25		25		25	mA
ICC ³	A42MX16		6		25		25		25	mA
	A42MX24, A42MX36		20		25		25		25	mA
Low Power Mode Standby Current			0.5		ICC - 5.0		ICC - 5.0		ICC - 5.0	mA

Table 22 • Mixed 5.0V/3.3V Electrical Specifications

IIO I/O source sink Can be derived from the *IBIS model* (http://www.microsemi.com/soc/techdocs/models/ibis.html) current

1. Only one output tested at a time. VCCI = min.

2. VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V

3. All outputs unloaded. All inputs = VCCI or GND

3.9.2 Output Drive Characteristics for 5.0 V PCI Signaling

MX PCI device I/O drivers were designed specifically for high-performance PCI systems. Figure 16, page 28 shows the typical output drive characteristics of the MX devices. MX output drivers are compliant with the PCI Local Bus Specification.

Table 23 • DC Specification (5.0 V PCI Signaling)¹

			PCI		MX		
Symbol	Parameter	Condition	Min.	Max.	Min.	Max.	Units
VCCI	Supply Voltage for I/Os		4.75	5.25	4.75	5.25 ²	V
VIH ³	Input High Voltage		2.0	VCC + 0.5	2.0	VCCI + 0.3	V
VIL	Input Low Voltage		-0.5	0.8	-0.3	0.8	V
IIH	Input High Leakage Current	VIN = 2.7 V		70	—	10	μA
IIL	Input Low Leakage Current	VIN=0.5 V		-70	—	-10	μA
VOH	Output High Voltage	IOUT = -2 mA IOUT = -6 mA	2.4		3.84		V
VOL	Output Low Voltage	IOUT = 3 mA, 6 mA		0.55	_	0.33	V

Table 23 • DC Specification (5.0 V PCI Signaling)¹

			PCI		MX	MX		
Symbol	Parameter	Condition	Min.	Max.	Min.	Max.	Units	
C _{IN}	Input Pin Capacitance			10	—	10	pF	
C _{CLK}	CLK Pin Capacitance		5	12	—	10	pF	
L _{PIN}	Pin Inductance			20	_	< 8 nH ⁴	nH	

1. PCI Local Bus Specification, Version 2.1, Section 4.2.1.1.

2. Maximum rating for VCCI -0.5 V to 7.0 V

3. VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V.

4. Dependent upon the chosen package. PCI recommends QFP and BGA packaging to reduce pin inductance and capacitance.

Table 24 • AC Specifications (5.0V PCI Signaling)*

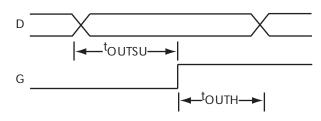
			PCI	MX			
Symbol	Parameter	Condition	Min.	Max.	Min.	Max.	Units
ICL	Low Clamp Current	$-5 < VIN \le -1$	-25 + (VIN +1) /0.015		-60	-10	mA
Slew (r)	Output Rise Slew Rate	0.4 V to 2.4 V load	1	5	1.8	2.8	V/ns
Slew (f)	Output Fall Slew Rate	2.4 V to 0.4 V load	1	5	2.8	4.3	V/ns

Note: *PCI Local Bus Specification, Version 2.1, Section 4.2.1.2.



Figure 27 • Output Buffer Latches

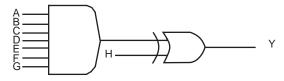


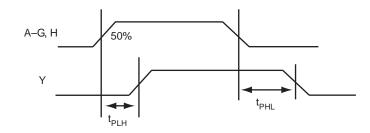


3.10.4 Decode Module Timing

The following figure shows decode module timing.

Figure 28 • Decode Module Timing





3.10.5 SRAM Timing Characteristics

The following figure shows SRAM timing characteristics.

Figure 29 • SRAM Timing Characteristics

Write Port		Read Port	
 WRAD [5:0] BLKEN WEN WCLK WD [7:0]	RAM Array 32x8 or 64x4 (256 Bits)	RDAD [5:0] LEW REN RCLK RD [7:0]	

3.10.6 Dual-Port SRAM Timing Waveforms

The following figures show dual-port SRAM timing waveforms.



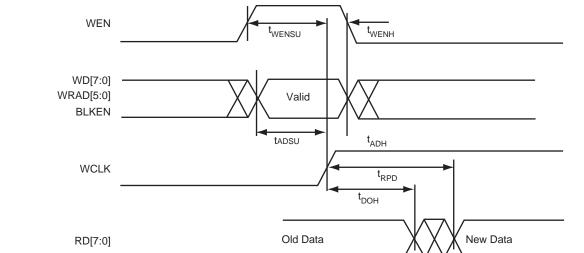


Figure 33 • 42MX SRAM Asynchronous Read Operation—Type 2 (Write Address Controlled)

3.10.7 Predictable Performance: Tight Delay Distributions

Propagation delay between logic modules depends on the resistive and capacitive loading of the routing tracks, the interconnect elements, and the module inputs being driven. Propagation delay increases as the length of routing tracks, the number of interconnect elements, or the number of inputs increases.

From a design perspective, the propagation delay can be statistically correlated or modeled by the fanout (number of loads) driven by a module. Higher fanout usually requires some paths to have longer routing tracks.

The MX FPGAs deliver a tight fanout delay distribution, which is achieved in two ways: by decreasing the delay of the interconnect elements and by decreasing the number of interconnect elements per path.

Microsemi's patented antifuse offers a very low resistive/capacitive interconnect. The antifuses, fabricated in 0.45 μ m lithography, offer nominal levels of 100 Ω resistance and 7.0 fF capacitance per antifuse.

MX fanout distribution is also tight due to the low number of antifuses required for each interconnect path. The proprietary architecture limits the number of antifuses per path to a maximum of four, with 90 percent of interconnects using only two antifuses.

3.11 Timing Characteristics

Device timing characteristics fall into three categories: family-dependent, device-dependent, and designdependent. The input and output buffer characteristics are common to all MX devices. Internal routing delays are device-dependent; actual delays are not determined until after place-and-route of the user's design is complete. Delay values may then be determined by using the Designer software utility or by performing simulation with post-layout delays.

3.11.1 Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most timing critical paths. Critical nets are determined by net property assignment in Microsemi's Designer software prior to placement and routing. Up to 6% of the nets in a design may be designated as critical.

3.11.2 Long Tracks

Some nets in the design use long tracks, which are special routing resources that span multiple rows, columns, or modules. Long tracks employ three and sometimes four antifuse connections, which increase capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically, up to 6 percent of nets in a fully utilized device require long tracks. Long tracks add



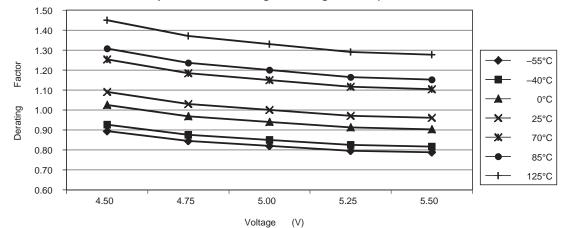


Figure 35 • 40MX Junction Temperature and Voltage Derating Curves (Normalized to TJ = 25°C, VCC = 5.0 V)

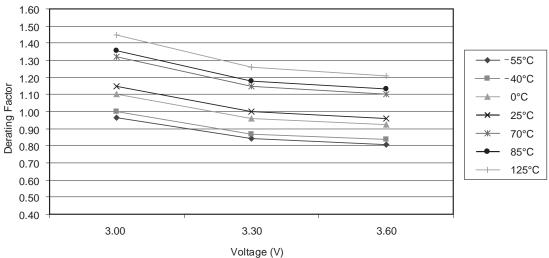
Note: This derating factor applies to all routing and propagation delays



	Temperature										
42MX Voltage	–55°C	–40°C	0°C	25°C	70°C	85°C	125°C				
3.00	0.97	1.00	1.10	1.15	1.32	1.36	1.45				
3.30	0.84	0.87	0.96	1.00	1.15	1.18	1.26				
3.60	0.81	0.84	0.92	0.96	1.10	1.13	1.21				

Figure 36 • 42MX Junction Temperature and Voltage Derating Curves

(Normalized to $TJ = 25^{\circ}C$, VCCA = 3.3 V)



Note: This derating factor applies to all routing and propagation delays

Table 31 • 40MX Temperature and Voltage Derating Factors (Normalized to TJ = 25°C, VCC = 3.3 V)

	Temperature											
40MX Voltage	–55°C	–40°C	0°C	25°C	70°C	85°C	125°C					
3.00	1.08	1.12	1.21	1.26	1.50	1.64	2.00					
3.30	0.86	0.89	0.96	1.00	1.19	1.30	1.59					



Table 43 •A42MX24 Timing Characteristics (Nominal 3.3 V Operation) (continued) (Worst-Case Commercial
Conditions, VCCA = 3.0 V, T_J = 70°C)

			–3 S	peed	–2 Sp	beed	–1 S	peed	Std S	speed	–F S	peed	
Paramet	ter / Description		Min.	Max.	Units								
Input Mo	odule Predicted Routing	Delays ²											
t _{IRD1}	FO = 1 Routing Delay			2.6		2.9		3.2		3.8		5.3	ns
t _{IRD2}	FO = 2 Routing Delay			2.9		3.2		3.6		4.3		6.0	ns
t _{IRD3}	FO = 3 Routing Delay			3.2		3.6		4.0		4.8		6.6	ns
t _{IRD4}	FO = 4 Routing Delay			3.5		3.9		4.4		5.2		7.3	ns
t _{IRD8}	FO = 8 Routing Delay			4.8		5.3		6.1		7.1		10.0	ns
Global C	Clock Network												
t _{CKH}	Input LOW to HIGH	FO = 32 FO = 486		4.4 4.8		4.8 5.3		5.5 6.0		6.5 7.1		9.1 10.0	ns ns
t _{CKL}	Input HIGH to LOW	FO = 32 FO = 486		5.1 6.0		5.7 6.6		6.4 7.5		7.6 8.8		10.6 12.4	ns ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 32 FO = 486	3.0 3.3		3.3 3.7		3.8 4.2		4.5 4.9		6.3 6.9		ns ns
t _{PWL}	Minimum Pulse Width LOW	FO = 32 FO = 486	3.0 3.3		3.4 3.7		3.8 4.2		4.5 4.9		6.3 6.9		ns ns
t _{CKSW}	Maximum Skew	FO = 32 FO = 486		0.8 0.8		0.8 0.8		1.0 1.0		1.1 1.1		1.6 1.6	ns ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32 FO = 486	0.0 0.0		ns ns								
TTL Out	put Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH			3.4		3.8		4.3		5.0		7.1	ns
t _{DHL}	Data-to-Pad LOW			4.0		4.4		5.0		5.9		8.3	ns
t _{ENZH}	Enable Pad Z to HIGH			3.6		4.0		4.5		5.3		7.4	ns
t _{ENZL}	Enable Pad Z to LOW			3.9		4.4		5.0		5.8		8.2	ns
t _{ENHZ}	Enable Pad HIGH to Z			7.2		8.0		9.1		10.7		14.9	ns
t _{ENLZ}	Enable Pad LOW to Z			6.7		7.5		8.5		9.9		13.9	ns
t _{GLH}	G-to-Pad HIGH			4.8		5.3		6.0		7.2		10.0	ns
t _{GHL}	G-to-Pad LOW			4.8		5.3		6.0		7.2		10.0	ns
t _{LSU}	I/O Latch Output Set-U	р	0.7		0.7		0.8		1.0		1.4		ns



Table 44 •A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions,
VCCA = 4.75 V, T_J = 70°C)

		–3 S	peed	–2 S	beed	–1 Sp	beed	Std S	peed	–F Sp	beed	
Parame	eter / Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
TTL Ou	tput Module Timing ⁵ (Continued)											
t _{ENLZ}	Enable Pad LOW to Z		4.9		5.5		6.2		7.3		10.2	ns
t _{GLH}	G-to-Pad HIGH		2.9		3.3		3.7		4.4		6.1	ns
t _{GHL}	G-to-Pad LOW		2.9		3.3		3.7		4.4		6.1	ns
t _{LSU}	I/O Latch Output Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Output Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.7		6.3		7.1		8.4		11.8	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.8		8.6		9.8		11.5		16.1	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.07		0.08		0.09		0.10		0.14	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.07		0.08		0.09		0.10		0.14	ns/pF



Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

		–3 SI	beed	–2 S	peed	–1 Sp	beed	Std S	Speed	–F S	peed	
Paramete	er / Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Synchro	nous SRAM Operations (continue	ed)										
t _{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t _{RENSU}	Read Enable Set-Up	0.9		1.0		1.1		1.3		1.8		ns
t _{RENH}	Read Enable Hold	4.8		5.3		6.0		7.0		9.8		ns
t _{WENSU}	Write Enable Set-Up	3.8		4.2		4.8		5.6		7.8		ns
t _{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{BENS}	Block Enable Set-Up	3.9		4.3		4.9		5.7		8.0		ns
t _{BENH}	Block Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
Asynchr	onous SRAM Operations											
t _{RPD}	Asynchronous Access Time		11.3		12.6		14.3		16.8		23.5	ns
t _{RDADV}	Read Address Valid	12.3		13.7		15.5		18.2		25.5		ns
t _{ADSU}	Address/Data Set-Up Time	2.3		2.5		2.8		3.4		4.8		ns
t _{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t _{RENSUA}	Read Enable Set-Up to Address Valid	0.9		1.0		1.1		1.3		1.8		ns
t _{RENHA}	Read Enable Hold	4.8		5.3		6.0		7.0		9.8		ns
t _{WENSU}	Write Enable Set-Up	3.8		4.2		4.8		5.6		7.8		ns
t _{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{DOH}	Data Out Hold Time		1.8		2.0		2.1		2.5		3.5	ns
Input Mo	dule Propagation Delays											
t _{INPY}	Input Data Pad-to-Y		1.4		1.6		1.8		2.1		3.0	ns
t _{INGO}	Input Latch Gate-to-Output		2.0		2.2		2.5		2.9		4.1	ns
t _{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t _{ILA}	Latch Active Pulse Width	6.5		7.3		8.2		9.7		13.5		ns



Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued) (Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

		–3 S	peed	-2 S	peed	–1 S	peed	Std S	Speed	–F S	peed	
Parame	ter / Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.9		12.1		13.7		16.1		22.5	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.10		0.11		0.12		0.14		0.20	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.10		0.11		0.12		0.14		0.20	ns/pF
CMOS	Output Module Timing ⁵											
t _{DLH}	Data-to-Pad HIGH		4.9		5.5		6.2		7.3		10.3	ns
t _{DHL}	Data-to-Pad LOW		3.4		3.8		4.3		5.1		7.1	ns
t _{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.7		5.5		7.7	ns
t _{ENZL}	Enable Pad Z to LOW		4.1		4.6		5.2		6.1		8.5	ns
t _{ENHZ}	Enable Pad HIGH to Z		7.4		8.2		9.3		10.9		15.3	ns
t _{ENLZ}	Enable Pad LOW to Z		6.9		7.6		8.7		10.2		14.3	ns
t _{GLH}	G-to-Pad HIGH		7.0		7.8		8.9		10.4		14.6	ns
t _{GHL}	G-to-Pad LOW		7.0		7.8		8.9		10.4		14.6	ns
t _{LSU}	I/O Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.9		8.8		10.0		11.8		16.5	ns

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.

4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

5. Delays based on 35 pF loading.

3.12 **Pin Descriptions**

This section lists the pin descriptions for 40MX and 42MX series FPGAs.

CLK/A/B, I/O Global Clock

Clock inputs for clock distribution networks. CLK is for 40MX while CLKA and CLKB are for 42MX devices. The clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

DCLK, I/ODiagnostic Clock

Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

GND, Ground

Input LOW supply voltage.

I/O, Input/Output



Figure 39 • PL68

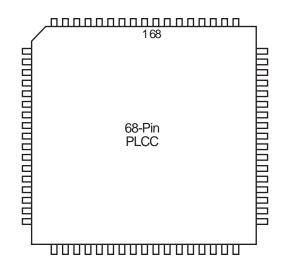


Table 48 • PL68

PL68		
Pin Number	A40MX02 Function	A40MX04 Function
1	I/O	I/O
2	I/O	I/O
3	I/O	I/O
4	VCC	VCC
5	I/O	I/O
6	I/O	I/O
7	I/O	I/O
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	GND	GND
15	GND	GND
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	I/O	I/O
21	VCC	VCC
22	I/O	I/O
23	I/O	I/O



Table 49 • PL84

PL84				
Pin Number	A40MX04 Function	A42MX09 Function	A42MX16 Function	A42MX24 Function
47	I/O	I/O	I/O	WD, I/O
48	I/O	I/O	I/O	I/O
49	I/O	GND	GND	GND
50	I/O	I/O	I/O	WD, I/O
51	I/O	I/O	I/O	WD, I/O
52	I/O	SDO, I/O	SDO, I/O	SDO, TDO, I/O
53	I/O	I/O	I/O	I/O
54	I/O	I/O	I/O	I/O
55	I/O	I/O	I/O	I/O
56	I/O	I/O	I/O	I/O
57	I/O	I/O	I/O	I/O
58	I/O	I/O	I/O	I/O
59	I/O	I/O	I/O	I/O
60	GND	I/O	I/O	I/O
61	GND	I/O	I/O	I/O
62	I/O	I/O	I/O	TCK, I/O
63	I/O	LP	LP	LP
64	CLK, I/O	VCCA	VCCA	VCCA
65	I/O	VCCI	VCCI	VCCI
66	MODE	I/O	I/O	I/O
67	VCC	I/O	I/O	I/O
68	VCC	I/O	I/O	I/O
69	I/O	I/O	I/O	I/O
70	I/O	GND	GND	GND
71	I/O	I/O	I/O	I/O
72	SDI, I/O	I/O	I/O	I/O
73	DCLK, I/O	I/O	I/O	I/O
74	PRA, I/O	I/O	I/O	I/O
75	PRB, I/O	I/O	I/O	I/O
76	I/O	SDI, I/O	SDI, I/O	SDI, I/O
77	I/O	I/O	I/O	I/O
78	I/O	I/O	I/O	WD, I/O
79	I/O	I/O	I/O	WD, I/O
80	I/O	I/O	I/O	WD, I/O
81	I/O	PRA, I/O	PRA, I/O	PRA, I/O
82	GND	I/O	I/O	I/O
83	I/O	CLKA, I/O	CLKA, I/O	CLKA, I/O



Figure 42 • PQ144

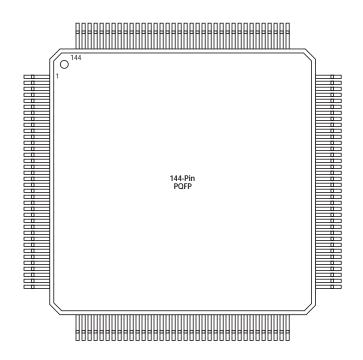


Table 51 • PQ144

PQ144		
Pin Number	A42MX09 Function	
1	I/O	
2	MODE	
3	I/O	-
4	I/O	
5	I/O	



Table 52 • PQ160

PQ160			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
21	CLKA, I/O	CLKA, I/O	CLKA, I/O
22	I/O	I/O	I/O
23	PRA, I/O	PRA, I/O	PRA, I/O
24	NC	I/O	WD, I/O
25	I/O	I/O	WD, I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	NC	I/O	I/O
29	I/O	I/O	WD, I/O
30	GND	GND	GND
31	NC	I/O	WD, I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	NC	VCCI	VCCI
36	I/O	I/O	WD, I/O
37	I/O	I/O	WD, I/O
38	SDI, I/O	SDI, I/O	SDI, I/O
39	I/O	I/O	I/O
40	GND	GND	GND
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	GND	GND	GND
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	GND	GND	GND
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	NC	I/O	I/O
53	I/O	I/O	I/O
54	NC	VCCA	VCCA
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	VCCA	VCCA	VCCA



Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
84	I/O	I/O	WD, I/O
85	I/O	I/O	WD, I/O
86	NC	I/O	I/O
87	SDO, I/O	SDO, I/O	SDO, TDO, I/O
88	I/O	I/O	I/O
89	GND	GND	GND
90	I/O	I/O	I/O
91	I/O	I/O	I/O
92	I/O	I/O	I/O
93	I/O	I/O	I/O
94	I/O	I/O	I/O
95	I/O	I/O	I/O
96	NC	I/O	I/O
97	NC	I/O	I/O
98	I/O	I/O	I/O
99	I/O	I/O	I/O
100	I/O	I/O	I/O
101	NC	NC	I/O
102	I/O	I/O	I/O
103	NC	I/O	I/O
104	I/O	I/O	I/O
105	I/O	I/O	I/O
106	GND	GND	GND
107	NC	I/O	I/O
108	NC	I/O	TCK, I/O
109	LP	LP	LP
110	VCCA	VCCA	VCCA
111	GND	GND	GND
112	VCCI	VCCI	VCCI
113	VCCA	VCCA	VCCA
114	NC	I/O	I/O
115	NC	I/O	I/O
116	NC	VCCA	VCCA
117	I/O	I/O	I/O
118	I/O	I/O	I/O
119	I/O	I/O	I/O
120	I/O	I/O	I/O



CQ208	
Pin Number	A42MX36 Function
37	I/O
38	I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	I/O
45	I/O
46	I/O
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	GND
53	GND
54	TMS, I/O
55	TDI, I/O
56	I/O
57	WD, I/O
58	WD, I/O
59	I/O
60	VCCI
61	I/O
62	I/O
63	I/O
64	I/O
65	QCLKA, I/O
66	WD, I/O
67	WD, I/O
68	I/O
69	I/O
70	WD, I/O
71	WD, I/O
72	I/O
73	I/O



Figure 50 • CQ256

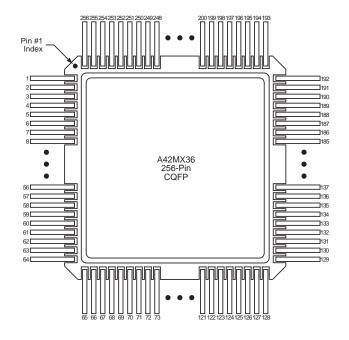


Table	59 •	CQ256

CQ256	
Pin Number	A42MX36 Function
1	NC
2	GND
3	I/O
4	I/O
5	I/O
6	I/O
7	I/O
8	I/O
9	I/O
10	GND
11	I/O
12	I/O
13	I/O
14	I/O
15	I/O
16	I/O
17	I/O
18	I/O
19	I/O
20	I/O
21	I/O



CQ256	
Pin Number	A42MX36 Function
22	I/O
23	I/O
24	I/O
25	I/O
26	VCCA
27	I/O
28	I/O
29	VCCA
30	VCCI
31	GND
32	VCCA
33	LP
34	TCK, I/O
35	I/O
36	GND
37	I/O
38	I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	I/O
45	I/O
46	I/O
47	I/O
48	GND
49	I/O
50	I/O
51	I/O
52	I/O
53	I/O
54	I/O
55	I/O
56	I/O
57	I/O
58	I/O